

|                                   |                                       |  |   |             |
|-----------------------------------|---------------------------------------|--|---|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/645,209 |  | Applicant(s)/Patent Under<br>Reexamination<br>CHAN ET AL. |             |
|                                   | Examiner<br>Ramesh B. Patel           |  | Art Unit<br>2121  | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                     | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| X | A | US-5,784,273 A                                   | 07-1998         | Madhavan, Poovanpilli G. | 700/71         |
| X | B | US-6,004,017 A                                   | 12-1999         | Madhavan, Poovanpilli G. | 700/71         |
| X | C | US-6,738,954 B1                                  | 05-2004         | Allen et al.             | 716/4          |
| X | D | US-2001/0032025 A1                               | 10-2001         | Lenz et al.              | 700/28         |
|   | E | US-  |                 |                          |                |
|   | F | US-  |                 |                          |                |
|   | G | US-  |                 |                          |                |
|   | H | US-  |                 |                          |                |
|   | I | US-  |                 |                          |                |
|   | J | US-  |                 |                          |                |
|   | K | US-  |                 |                          |                |
|   | L | US-  |                 |                          |                |
|   | M | US-  |                 |                          |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)   |
|---|---|---|
|   | U | Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance;Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.; Advanced Semiconductor Manufacturing Conference and Workshop, 2003 IEEE/SEMI , 31 March-1 April. |
|   | V | Utilization of the saturation effect on a DC motor drive with a fuzzy controller; Lee, C.K.; Chan, W.T.; Industrial Automation and Control: Emerging Technologies, 1995., International IEEE/IAS Conference on , 22-27 May 1995 , Pages:342 - 349.              |
|   | W | Precast production scheduling with genetic algorithms; Chan, W.T.; Hu, H.; Evolutionary Computation, 2000. Proceedings of the 2000 Congress on ,Volume: 2 , 16-19 July 2000, Pages:1087 - 1094 vol.2.   |
|   | X | Predicting failure modes to improve reliability; Reid, J.M.; Reliability and Maintainability Symposium, 1990. Proceedings., Annual , 23-25 Jan. 1990,Pages:497 - 500.   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.